

Substitute Form PTO-1449 Revised 01/98	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 05542-146004	Application No. 09/399,310
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR 1.98(b))		Applicant Manoocher Birang et al.	
		Filing Date September 20, 1999	Group Art Unit Unknown

U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
PJC	AA	4,927,485	05/22/1990	Cheng et al.			
PJC	AB	5,081,796	01/21/1992	Schultz			
PJC	AC	5,196,353	03/23/93	Sandhu, et al.			
PJC	AD	5,257,478	11/02/93	Hyde et al.			
PJC	AE	5,413,941	05/1995	Koos et al.			
PJC	AF	5,433,651	7/1995	Lustig et al.			
PJC	AG	5,489,233	02/06/1996	Cook et al.			
PJC	AH	5,499,733	03/19/1996	Litvak			
PJC	AI	5,605,760	02/25/1997	Roberts			
PJC	AJ	5,609,511	03/11/1997	Moriyama et al.			
PJC	AK	5,946,927	09/07/1999	Dieckmann et al.			
PJC	AL	5,964,643	10/12/1999	Birang et al.	451	6	
PJC	AM	6,045,439	04/04/2000	Birang et al.	451	526	
PJC	AN	6,280,290	08/28/2001	Birang et al.			
PJC	AO	6,524,164	02/25/2003	Tolles			
PJC	AP	6,537,133	03/25/2003	Birang et al.	451	6	

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
PJC	AQ	EP 0663265	03/06/1998	Europe				
PJC	AR	FR-A-1 075 634	10/1954	France			X	
PJC	AS	JP 3-234467	10/18/91	Abstract Of Japan			X	
PJC	AT	JP 5-138531	06/01/93	Abstract Of Japan			X	
PJC	AU	JP 07-52032	02/07/1995	Abstract Of Japan			X	
PJC	AV	JP 57-138575	08/26/1982	Abstract Of Japan			X	
PJC	AW	JP 58-178526	10/19/1983	Abstract Of Japan			X	
PJC	AX	WO 93/20976	10/1993	WIPO				

Examiner Signature PATRICK CONNELLY	Date Considered 05.20.2004
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 05542-146004	Application No. 09/399,310
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.96(b))		Applicant Manoocher Birang et al.	
		Filing Date September 20, 1999	Group Art Unit Unknown

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
PJC	AY	Hench, "In situ real-time ellipsometry for film thickness measurement and control," J. Vac. Sci. Technol. A. Vol. 10, No. 4:934-938 (Jul/Aug. 1992).
PJC	AZ	Sautter, et al., "Development Process Control and Optimization Utilizing an End Point Monitor," SPIE Vol. 1087:312-321 (1989).
PJC	AAA	Jurczyk, et al., "Process Detection System," IBM Technical Disclosure Bulletin, Vol. 18 No. 6:1867-1870 (November 1975).
PJC	ABB	Anonymous, "End-Point Detection of Oxide Polishing and Planarization of Semiconductor Devices," Research Disclosure, No. 340 (August 1992).
PJC	ACC	Rodel, "Wafer Mounting Assemblies and Materials", ©1992 Rodel, Scottsdale, Arizona.
PJC	ADD	Carotta, et al., "Effect of Thickness and Surface Treatment on Silicon Water Reflectance," Solar Energy Materials and Solar Cells 27: 265-272 (1992).
PJC	AEE	Rodel, "Glass Polishing Pads", January 1993, Scottsdale, Arizona

Examiner Signature PATRICK CONNOLLY	Date Considered 05.20.2004
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STATEMENT BY APPLICANT
(Use several sheets if necessary)APPLICANT
Manoocher Birang et al.FILING DATE
September 20, 1999

GROUP

(37 CFR 1.98(b))

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER							ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
PJC	AA	5	9	4	9	9	2	7	09-07-99	Tang			
	AB												
	AC												
	AD												
	AE												
	AF												
	AG												
	AH												
	AI												
	AJ												
	AK												

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication)

	AQ							
	AR							
	AS							

EXAMINER

PATRICK CONNOLLY

DATE CONSIDERED

05-20-2004

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